TOSHIBA Field Effect Transistor Silicon N Channel MOS Type

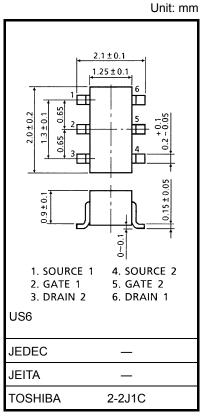
HN1K05FU

For Portable Devices
High Speed Switching Applications
Interface Applications

- High input impedance and extremely low drive current.
- V_{th} is low and it is possible to drive directly at low-voltage CMOS. : V_{th} = 0.5 to 1.0 V
- Suitable for high-density mounting because of a compact package.

Absolute Maximum Ratings (Ta = 25°C) (Q1, Q2 common)

Characteristics	Symbol	Rating	Unit
Drain-source voltage	V_{DS}	20	V
Gate-source voltage	V_{GSS}	10	V
DC drain current	ID	100	mA
Drain power dissipation	P _D (Note 1)	200	mW
Channel temperature	T _{ch}	150	°C
Storage temperature range	T _{stg}	-55 to 150	°C



Weight: 6.8 mg

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

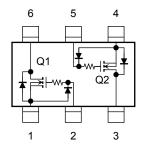
Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 1: TOTAL rating

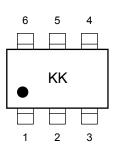
Electrical Characteristics (Ta = 25°C) (Q1, Q2 common)

Characteristic	Symbol	Test Condition	Min	Тур.	Max	Unit	
Gate leakage current	I _{GSS}	V _{GS} = 10 V, V _{DS} = 0 V	_	_	1	μА	
Drain-source breakdown voltage	V (BR) DSS	$I_D = 100 \mu A, V_{GS} = 0 V$	20	_	_	V	
Drain cut-off current	I _{DSS}	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}$		_	1	μΑ	
Gate threshold voltage	V_{th}	$V_{DS} = 1.5 \text{ V}, I_D = 0.1 \text{ mA}$	0.5	_	1	V	
Forward transfer admittance	Y _{fs}	$V_{DS} = 1.5 \text{ V}, I_D = 10 \text{ mA}$	35	70	_	mS	
Drain-Source ON resistance 1	R _{DS} (ON) 1	$I_D = 1 \text{ mA}, V_{GS} = 1.2 \text{ V}$		15	50	Ω	
Drain-Source ON resistance 2	R _{DS} (ON) 2	$I_D = 10 \text{ mA}, V_{GS} = 1.5 \text{ V}$	_	10	40	Ω	
Drain-Source ON resistance 3	R _{DS} (ON) 3	$I_D = 10 \text{ mA}, V_{GS} = 2.5 \text{ V}$	_	7	28	Ω	
Input capacitance	C _{iss}	$V_{DS} = 1.5 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	_	12	_	pF	
Reverse transfer capacitance	C _{rss}	$V_{DS} = 1.5 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	_	3.4	_	pF	
Output capacitance	Coss	$V_{DS} = 1.5 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	_	12	_	pF	
Switching time	t _{on}	$V_{DD} = 1.5 \text{ V}, I_D = 10 \text{ mA}, V_{GS} = 0 \text{ to } 1.5 \text{ V}$		0.35	_	0	
	t _{off}	$V_{DD} = 1.5 \text{ V}, I_D = 10 \text{ mA}, V_{GS} = 0 \text{ to } 1.5 \text{ V}$	_	0.2	_	μS	

Equivalent Circuit (top view)



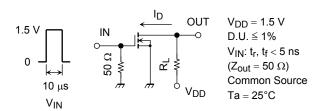
Marking



(Q1, Q2 common)

Switching Time Test Circuit

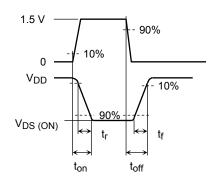
(a) Test circuit



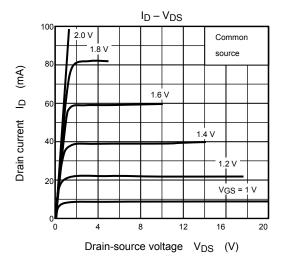
(b) V_{IN}

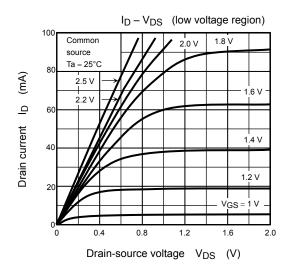


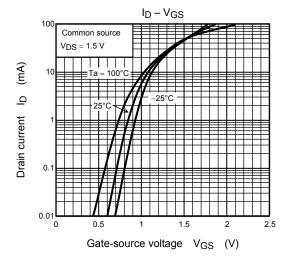


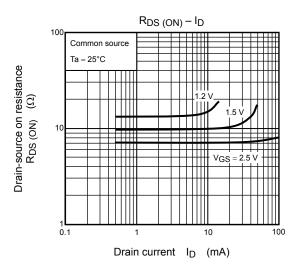


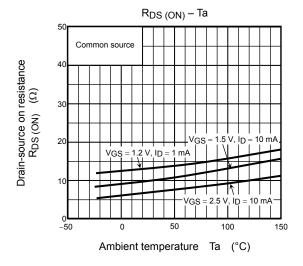
(Q1, Q2 common)

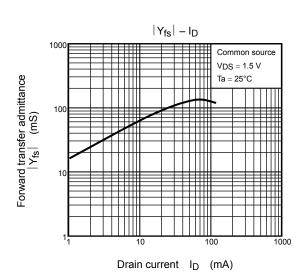






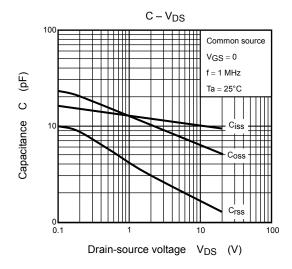


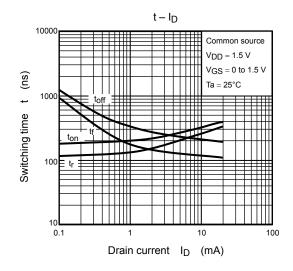


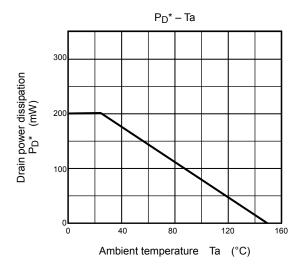


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(Q1, Q2 common)







*: TOTAL rating

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20070701-EN GENERAL

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